

# RELIABILITY MONITOR

| PRODUCT | MONITOR DATE | DATE CODE | ASSEMBLY FACILITY | ASSEMBLY LOT NO | PROCESS TYPE     | PACKAGE TYPE |
|---------|--------------|-----------|-------------------|-----------------|------------------|--------------|
| DS2502  | Dec-96       | 9641 A6   | CARSEM            | DM631365ABA1    | 1.2μ OX/NI EPROM | 08 SOIC 150  |

**STRESS/JOB NO.**

**READPOINT  
(Sample Size/No. of Fails)**

Preconditioning (P/C):  
HTC Vapor Phase  
P-18987

|                   |              |
|-------------------|--------------|
| <u>Electrical</u> | <u>Cum %</u> |
| 245/0             | 0.0%         |

Infant / High Voltage Life  
125°C, 7.0 V.  
P-19062, P-19095

|                           |              |               |             |                      |
|---------------------------|--------------|---------------|-------------|----------------------|
| <u>0 Hr</u>               | <u>48 Hr</u> | <u>336 Hr</u> | <u>1KHr</u> | <u>*Failure Rate</u> |
| 245/0                     | 241/0        | 77/0          | 77/0        | 30 Fits              |
| <small>Write Data</small> |              |               |             |                      |

\*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle  
-55°C to +125°C  
P-19096

|              |             |              |
|--------------|-------------|--------------|
| <u>300 ~</u> | <u>1K ~</u> | <u>Cum %</u> |
| 39/0         | 39/0        | 0.0%         |

Biased Moisture  
85°C/85% RH, 5.5 V.  
P-19097

|               |               |              |
|---------------|---------------|--------------|
| <u>274 Hr</u> | <u>959 Hr</u> | <u>Cum %</u> |
| 77/0          | 77/0          | 0.0%         |

Storage Life  
150°C, No bias  
P-19098

|               |             |              |
|---------------|-------------|--------------|
| <u>336 Hr</u> | <u>1KHr</u> | <u>Cum %</u> |
| 32/0          | 32/0        | 0.0%         |

**Failure Mode**

**Failure Analysis**